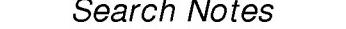


<i>Search Notes</i> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/646,615	HENNEN, WILLIAM J.	
	Examiner Taeyoon Kim	Art Unit 1651	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner